

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	09/704,595	AKKERMANS, ANTONIUS H.M.	
	Examiner	Art Unit	
	Jorge L Ortiz-Criado	2697	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,561,082	12-1985	Gerard et al.	369/44.34
*	B	US-5,636,197	06-1997	Tateishi, Kiyoshi	369/44.34
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/704,595	AKKERMANS, ANTONIUS H.M.	
Examiner		Art Unit		Page 1 of 1
Jorge L Ortiz-Criado		2697		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,561,082	12-1985	Gerard et al.	369/44.34
	B	US-5,636,197	06-1997	Tateishi, Kiyoshi	369/44.34
	C	US-5,228,019	07-1993	Yanagi, Shigenori	369/44.28
	D	US-4,813,031	03-1989	Bierhoff, Martinus P. M.	369/44.34
	E	US-5,856,959	01-1999	Yanagisawa, Takuma	369/44.23
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.